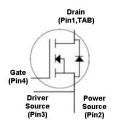


#### **Main Product Characteristics:**

V <sub>DS</sub>	1200V
I <sub>D</sub>	38A
R <sub>DS(on)</sub>	70mΩ





Schematic Diagram

#### **Features and Benefits:**

- High blocking voltage with low on-resistance
- High speed switching, very low switching losses
- High blocking voltage with low on-resistance
- Fast intrinsic diode with low reverse recovery (Qrr)
- Temperature independent turn-off switching losses

# RoHS Compliant

#### **Applications:**

- On-board charger/PFC
- EV battery chargers
- Booster/DC-DC converter
- Switch mode power supplies

## **Absolute Max Rating:**

Symbol	Parameter	Value	Units
V <sub>DS</sub>	Drain Source Voltage	1200	V
$V_{GS,max}$	Gate Source Voltage, Absolute Maximum Values	-8 /+22	V
$V_{GS,op}$	Gate Source Voltage,Recommended Operational Values	-4 /+18	V
	Continuous Drain Current @Tc = 25 °C	38	
ID	Continuous Drain Current @T <sub>C</sub> = 100 °C	27	Α
I <sub>D(puls)</sub>	Pulsed Drain Current,Pulse Width t <sub>P</sub> limited by T <sub>j,max</sub>	80	
P <sub>D</sub>	Power Dissipation @T <sub>C</sub> = 25°C, T <sub>J</sub> = 175°C	214	W
T <sub>J</sub> T <sub>STG</sub>	Operating Junction and Storage Temperature Range	-55 to +175	°C
TL	Soldering Temperature	260	°C

**Version: Preliminary** 



#### **Thermal Resistance**

Symbol	Characterizes	Тур.	Max.	Units
R <sub>θJC</sub>	Thermal Resistance,Junction-to-case	_	0.7	°C/W
R <sub>θJA</sub>	Thermal Resistance,Junction-to-ambient	_	35	°C/W

## **Electrical Characteristics** @T<sub>A</sub>=25°C unless otherwise specified

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions	
V <sub>(BR)DSS</sub>	Drain-to-Source Breakdown Voltage	1200	_	_	V	V <sub>GS</sub> = 0V, I <sub>D</sub> = 100μA	
Б	01 11 12 13 14 15 15 14 1	_	70	85	0	V <sub>GS</sub> =18V,I <sub>D</sub> = 20A	
$R_{DS(on)}$	Static Drain-to-Source On-resistance	_	110	_	mΩ	V <sub>GS</sub> =18V,I <sub>D</sub> =20A,T <sub>J</sub> =175°C	
V <sub>GS(th)</sub>	Gate Threshold Voltage	2.3	_	3.6	V	$V_{DS} = V_{GS}$ , $I_D = 5mA$	
I <sub>DSS</sub>	Drain-to-Source Leakage Current	_	_	10	μA	V <sub>DS</sub> = 1200V,V <sub>GS</sub> = 0V	
I <sub>GSS</sub>	Gate-to-Source Forward Leakage	_	_	100	nA	V <sub>GS</sub> =18V,V <sub>DS</sub> = 0V	
gfs	Transconductance	_	10	_	S	V <sub>DS</sub> = 20V, I <sub>D</sub> =20A	
Rg	Internal Gate Resistance	_	1.5	_	Ω	V <sub>AC</sub> = 25mV, f =1MHz	
Qg	Total Gate Charge	_	39	_		V <sub>DS</sub> = 800V,	
Q <sub>gs</sub>	Gate-to-Source Charge	_	8	_	nC	$V_{GS} = -4/+18V$ ,	
Q <sub>gd</sub>	Gate-to-Drain("Miller") Charge	_	18	_		I <sub>D</sub> = 20A	
$t_{\text{d(on)}}$	Turn-on Delay Time	_	11	_		$V_{DS}$ = 800V, $V_{GS}$ =-4/+15V $I_{D}$ = 20A, $Rg$ = 0 $\Omega$ L = 120uH	
t <sub>r</sub>	Rise Time	_	8	_	no		
$t_{\text{d(off)}} \\$	Turn-Off Delay Time	_	14	_	ns		
tf	Fall Time	_	8	_			
Eon	Turn on Switching Energy	_	81	_	1	- L - 120un	
E <sub>off</sub>	Turn off Switching Energy	_	25	_	μJ		
C <sub>iss</sub>	Input Capacitance	_	922	_	pF	V <sub>GS</sub> = 0V	
Coss	Output Capacitance	_	58	_			
Crss	Reverse Transfer Capacitance	_	4	_		$V_{DS} = 1000V$ f = 1MHz	
Eoss	Coss Stored Energy	_	36	_	μJ		

# Electrical Characteristics of the Diode@T<sub>A</sub>=25°C unless otherwise specified

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous diode forward current	_	38	_	Α	Tc = 25°C
V <sub>SD</sub>	Diode Forward Voltage	_	4.3	_	V	V <sub>GS</sub> = -4V, I <sub>SD</sub> = 10A
trr	Reverse recovery time	_	37.6	_	ns	\/ - 000\/ \/ - 4\/
Q <sub>rr</sub>	Reverse Recovery Charge	_	306	_	nC	$V_R = 800V$ , $V_{GS} = -4V$ $I_D = 20A$ , $di/dt =$ $2670A/\mu S$ , $T_J = 150^{\circ} C$
I <sub>RRM</sub>	Diode Peak Reverse Recovery	_	16	_	А	
	Current					



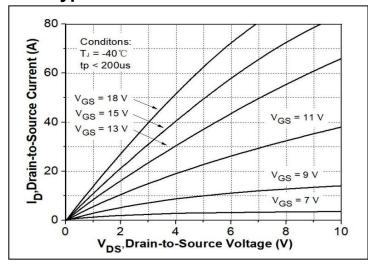


Figure 1. Typical Output Characteristics@T<sub>J</sub>=-40 °C

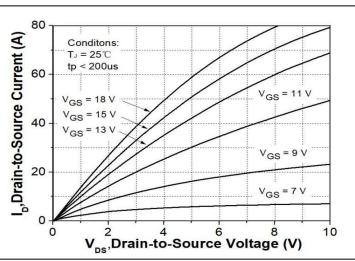


Figure2. Typical Output Characteristics@T<sub>J</sub>=25℃

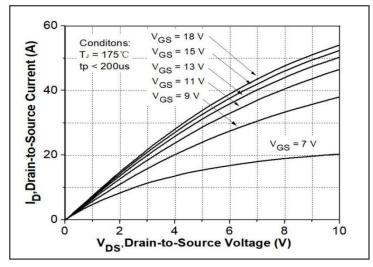


Figure3.Typical Output Characteristics@T<sub>J</sub>=175℃

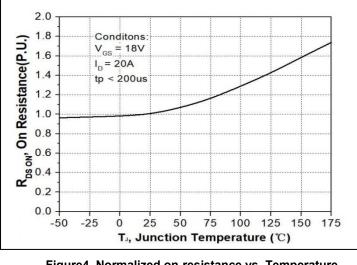


Figure 4. Normalized on-resistance vs. Temperature

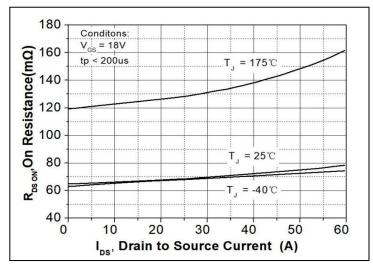


Figure 5. On-resistance vs. Drain Current

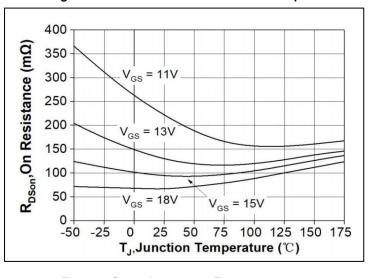
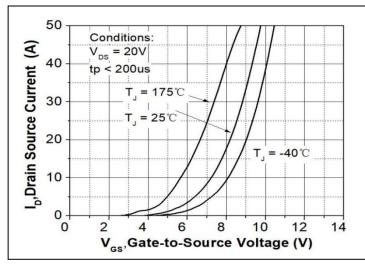


Figure 6. On-resistance vs. Temperature





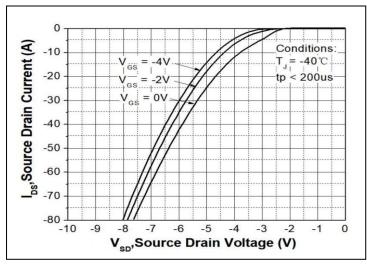
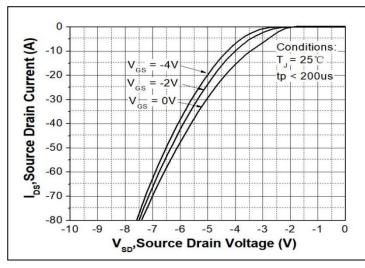


Figure 7. Transfer Characteristic for Various Junction Temperatures

Figure 8. Body Diode Characteristic @T<sub>J</sub> = -40 °C



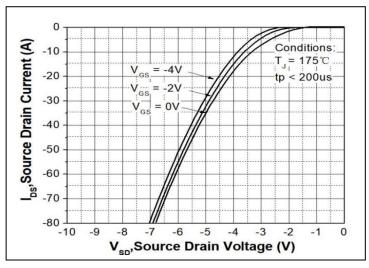
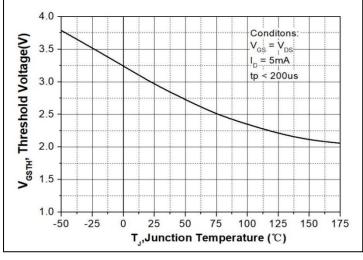


Figure 9. Body Diode Characteristic @T<sub>J</sub> = 25 °C

Figure 10. Body Diode Characteristic @T<sub>J</sub> = 175 °C



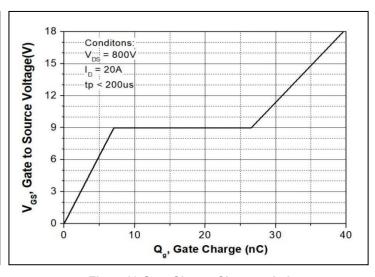


Figure 11. Threshold Voltage vs. Temperature

Figure 12. Gate Charge Characteristic



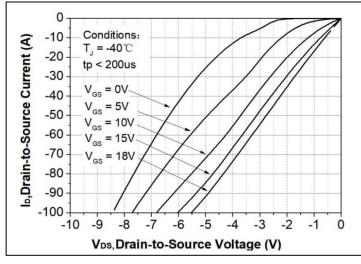


Figure 13.3rd Quadrant Characteristic @ T<sub>J</sub> = -40 °C

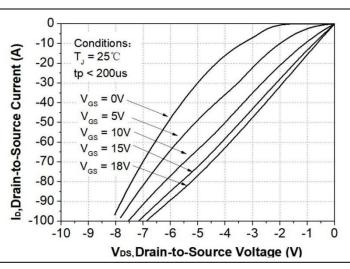


Figure 14.3rd Quadrant Characteristic @ T<sub>J</sub> = 25 °C

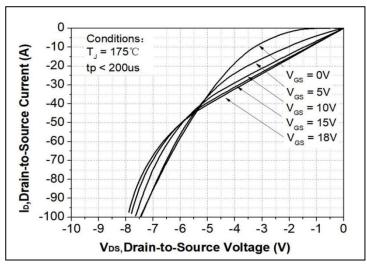


Figure15.3rd Quadrant Characteristic @ T<sub>J</sub> = 175 °C

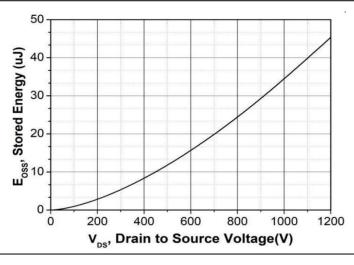


Figure16.Output Capacitor Stored Energy

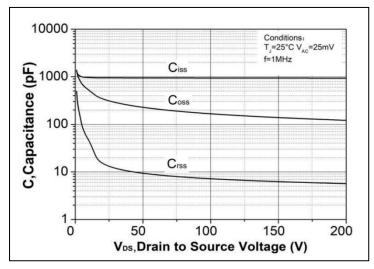


Figure17.Capacitances vs. Drain-source Voltage (0~200V)

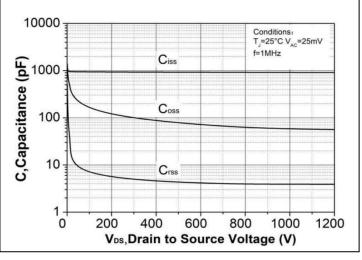


Figure 18. Capacitances vs. Drain-source Voltage (0~1200V)



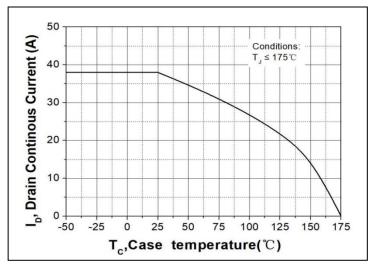


Figure 19. Continuous Drain Current Derating vs. Case Temperature

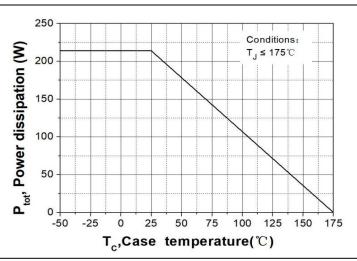


Figure 20. Maximum Power Dissipation Derating vs. Case **Temperature** 

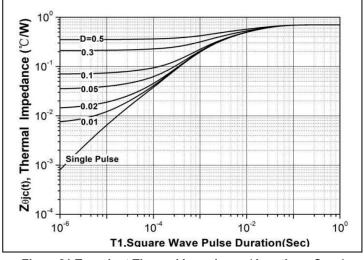


Figure 21. Transient Thermal Impedance (Junction - Case)

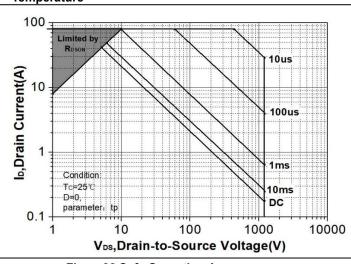
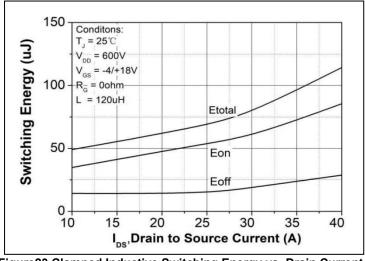


Figure 22. Safe Operating Area



 $(V_{DD} = 600V)$ 

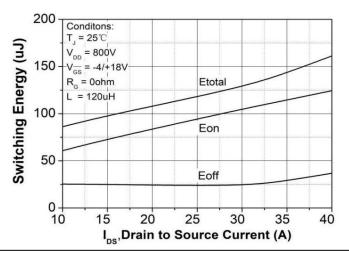
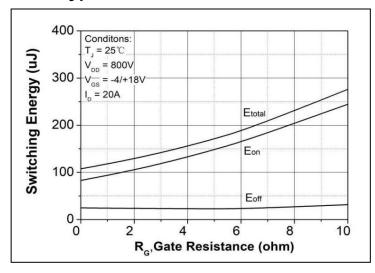


Figure 23. Clamped Inductive Switching Energy vs. Drain Current Figure 24. Clamped Inductive Switching Energy vs. Drain Current  $(V_{DD} = 800V))$ 





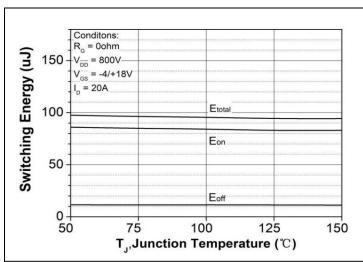
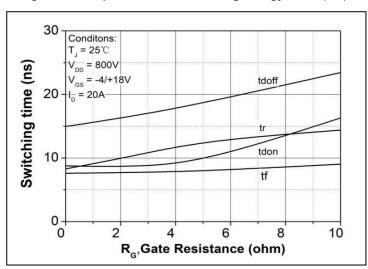


Figure 25. Clamped Inductive Switching Energy vs. R<sub>G</sub>(ext)

Figure 26. Clamped Inductive Switching Energy vs. Temperature



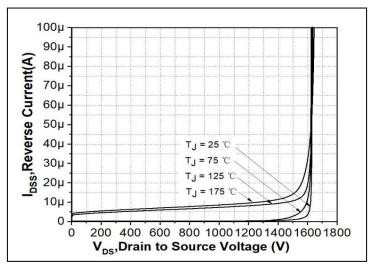


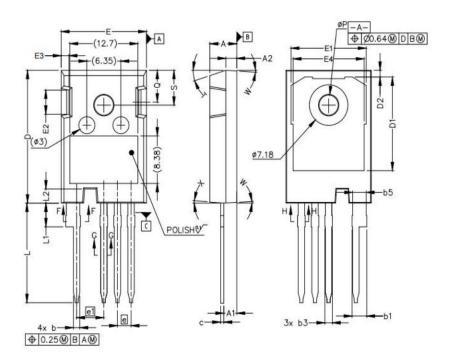
Figure 27. Switching Times vs. R<sub>G</sub>(ext)

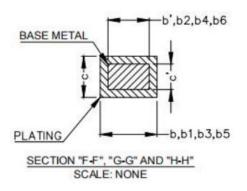
Figure 28. Reverse characteristics vs.TJ



#### **Mechanical Data:**

#### Unit:mm





CVAIDOL	MILLIMETERS			
SYMBOL	MIN	MAX		
Α	4.83	5.21		
A1	2.29	2.54		
A2	1.91	2.16		
b'	1.07	1.28		
b	1.07	1.33		
b1	2.39	2.94		
b2	2.39	2.84		
b3	1.07	1.60		
b4	1.07	1.50		
b5	2.39	2.69		
b6	2.39	2.64		
c'	0.55	0.65		
С	0.55	0.68		
D	23.30	23.60		
D1	16.25	17.65		
D2	0.95	1.25		
Е	15.75	16.13		
E1	13.10	14.15		
E2	3.68	5.10		
E3	1.00	1.90		
E4	12.38	13.43		
е	2.54 BSC			
e1	5.08	BSC		
N	4			
L	17.31	17.82		
L1	3.97	4.37		
L2	2.35	2.65		
øР	3.51	3.65		
Q	5.49	6.00		
S	6.04	6.30		
T	17.5° F	REF.		
W	3.5 ° REF.			
X	4° F	REF.		





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**Version:Preliminary**